

TEST REPORT

Applicant Name: Fanvil Link Technology Co.,LTD
Address: 13th Floor, Building 2, Runzhi R&D Center, Xin'an Street,
Bao'an District, Shenzhen, Guangdong, China
Report Number: 2501A04738E-RF-07

Test Standard (s)

Item 19 of Article 2 Paragraph 1

Sample Description

Product Type: Bluetooth Wireless Headset
Model No.: DH301B
Multiple Model(s) No.: N/A
Trade Mark: **LINKVIL**
Date Received: 2025-12-22
Issue Date: 2026-01-28

Test Result:	Pass▲
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▲ In the configuration tested, the EUT complied with the standards above.

Prepared and Checked By:

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GaLa Liu
RF Engineer

Approved By:

Jimmy Xiao

Jimmy Xiao
EMC Manager

Note: The information marked* is provided by the applicant, the laboratory is not responsible for its authenticity and this information can affect the validity of the result in the test report. Customer model name, addresses, names, trademarks etc. are included.

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DOCUMENT REVISION HISTORY

Revision Number	Report Number	Description of Revision	Date of Revision
0	2501A04738E-RF-07	Original Report	2026-01-28

GENERAL INFORMATION

Product Description for Equipment under Test (EUT)

Technical Parameters	Radio Type	Bluetooth
	Modulation Type	GFSK, $\pi/4$ -DQPSK, 8DPSK
	Frequency Range	2402-2480MHz
	Rated Output Power	0.03mW/MHz for BDR/EDR Mode
	Antenna Gain[#]	3.37dBi (It is provided by the applicant)
Nominal Power Supply		DC 3.7V from battery
Sample serial number		3EW4-3 (Assigned by BACL, Shenzhen)
Sample/EUT Status		Good condition
Adapter Information		N/A

Objective

The objective of the manufacturer is to demonstrate compliance with Certification Ordinance Article 2-1-19, rules and limits for this device including:

- Frequency Error
- Occupied Bandwidth and Spreading Bandwidth
- Transmitter Spurious Emission and Unwanted Emission Intensity
- Antenna Output Power And Output Power Tolerance
- Receiver Spurious Emission Strength
- Frequency Hopping Dwell Time
- Interference Prevention Function
- Construction Protection Confirmation

Test Method

MIC Notice No.88 of Jan. 26, 2004, Appendix No.43 (Latest version: MIC Notice No.373 of Nov. 8, 2023)

Measurement Uncertainty

Item	Expanded Measurement uncertainty
Frequency Error	81.235Hz(k=1.96, 95% level of confidence)
Occupied Channel Bandwidth	52.29kHz(k=1.96, 95% level of confidence)
RF output power, conducted	1.57dB(k=1.96, 95% level of confidence)
Unwanted Emission, conducted	2.48dB(k=1.96, 95% level of confidence)
Duty Cycle	±1%
Temperature	±0.4°C
Supply voltages	DC±0.4%;AC±1%
Humidity	±2%

Note: The extended uncertainty given in this report is obtained by combining the standard uncertainty times the coverage factor K with the 95% confidence interval. Otherwise required by the applicant or Product Regulations, Decision Rule in this report did not consider the uncertainty.

Test Facility

The Test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 5F(B-West) , 6F, 7F, the 3rd Phase of Wan Li Industrial Building D, Shihua Rd, FuTian Free Trade Zone, Shenzhen, China.

Each test item follows test standards and with no deviation.

EUT TEST CONFIGURATION

Description of Test Configuration

The system was configured for testing in a testing mode which was selected by manufacturer.

Normal/Extreme Voltage Condition [#]		
NV	Normal Voltage	3.70
LV	Low Voltage	3.43
HV	High Voltage	4.03
Note: extreme voltage test conditions were declared by manufacturer.		
The EUT works with a battery, power deviation of the RF circuit is less than 1% when extreme voltage supplied, therefore the test only performed at normal condition. Details as following:		
Voltage Condition	Input (V _{DC})	RF System Voltage (V _{DC})
NV	3.70	3.30
LV	3.43	3.28
HV	4.03	3.33

EUT Exercise Software

Exercise Software [#]	bt_tool_v1.1.2
Power Level [#]	6

Equipment Modifications

No modification was made to the EUT tested.

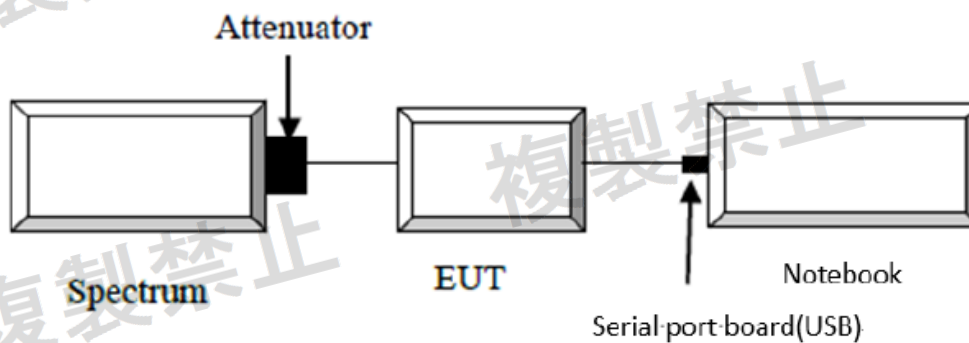
Support Equipment List and Details

Manufacturer	Description	Model	Serial Number
DELL	Notebook	Latitude E6410	11429208685
Unknown	Cable	Unknown	Unknown
Unknown	Serial Port board	TTL232	Unknown

External I/O Cable

Cable Description	Length(m)	From/Port	To
Non-detachable Wire Cable	0.2	EUT	Notebook

Configuration of Test Setup



SUMMARY OF TEST RESULTS

MIC Notice No.88 Appendix No.43 Article 2, Paragraph 1, Item 19	Description of Test	Result
1	Frequency Error	Compliant
2	Occupied Bandwidth and Spreading Bandwidth	Compliant
3	Transmitter Spurious Emission and Unwanted Emission Intensity	Compliant
4	Antenna Output Power and Output Power Tolerance	Compliant
5	Receiver Spurious Emission and Unwanted Emission Intensity	Compliant
6	Transmission Antenna Gain	Not Applicable
7	Transmission Radiation Angle Width	Not Applicable
8	Frequency Hopping Dwell Time	Compliant
9	Interference Prevention Function	Compliant
10	Construction Protection Confirmation ▼	Compliant

Not Applicable - This test item was not required for the output power less than 6.91 dBm/MHz (E.I.R.P)

TEST EQUIPMENT LIST

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Authority	Calibration Method
JD	JD Auto Test software	NA	1.0.0.3769	NCR	NCR	/	/
Unknown	10dB Attenuator	Unknown	F-03-EM224	2025/06/26	2026/06/25	BACL SZ	d)
JD	Multi-channel power acquisition unit	DT2400MPS	DS78928	2025/11/03	2026/11/02	BACL Cal	c)
JD	Switching control unit	DT2400MCU	DS78925	2025/11/03	2026/11/02	BACL Cal	c)
Rohde & Schwarz	Spectrum Analyzer	FSU26	200982	2025/08/12	2026/08/11	BACL Cal	c)
Rohde & Schwarz	Wideband Radio Communication Tester	CMW500	146520	2025/09/18	2026/09/17	CCIC	c)
Keysight	MXG Vector Signal Generator	N5182B	MY53051503	2025/09/18	2026/09/17	CCIC	c)

Note: Calibration Method

a) Calibration conducted by the National Institute of Information and Communications Technology (NICT) or a designated calibration agency under Article 102-18 paragraph (1)

b) Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992) ~Japan Calibration Service System~

c) Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1)

d) Calibration conducted by using other equipment that listed above from a) to c)

*** Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

REQUIREMENTS AND TEST PROCEDURES

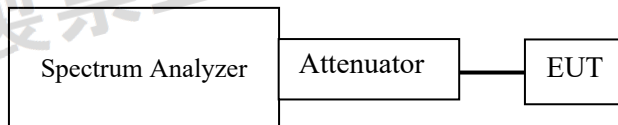
Frequency Error

Limit

50 ppm or below

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- Set the application equipment (EUT) to the measurement frequency.
- The modulation state shall be “continuous carrier wave without modulation” by stopping frequency-hopping mode.

Spectrum Analyzer Conditions

- Center Frequency: Frequency to measure (2402 MHz, 2441MHz, and 2480MHz)
- RBW: 1 kHz, VBW: 3 kHz
- Span: 300 kHz
- Sweep time: Auto
- Log scale: 10dB/Div, Data points: 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak
- Sweep mode: Single Sweep
- Marker: Spot

If the EUT can't set at un-modulation mode, measure the 10dBc center frequency.

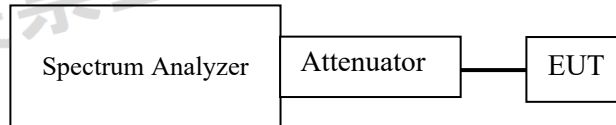
Occupied Bandwidth and Spreading Bandwidth

Limit

- Occupied bandwidth: FH $\leq$ 83.5 MHz; OFDM, DS $\leq$ 26 MHz; Others $\leq$ 26 MHz
- Spread Bandwidth: $\geq$ 500 kHz (FH,DS), Spread factor $>$ 5.

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be “continuous frequency-hopping mode” by spread spectrum.

Spectrum Analyzer Conditions

- RBW: 300 kHz
- VBW: 300 kHz
- Sweep time: Auto(Minimum time to ensure measurement accuracy.)
- Log scal: 10dB/Div
- Data points : 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak, Sweep mode: Continuous

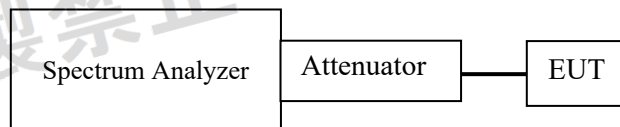
Transmitter Spurious Emission Strength and Unwanted Emission Intensity

Limit

- $f < 2387 \text{ MHz}$, $f > 2496.5 \text{ MHz}$: $\leq 2.5 \mu\text{W/MHz}$
- $2387 \text{ MHz} \leq f \leq 2400 \text{ MHz}$; $2483.5 \text{ MHz} < f \leq 2496.5 \text{ MHz}$: $\leq 25 \mu\text{W/MHz}$

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be in continuously transmitting mode.

Spectrum Analyzer Conditions

- Span: Measuring Frequency Range
- RBW: 1MHz (frequency range; 1GHz over), 100kHz (frequency range; 30MHz to 1GHz)
- VBW: Same as RBW (1MHz or 100kHz)
- Sweep time: Auto (Minimum time to ensure measurement accuracy.)
- Data points : 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak

If the test data above the limit, then the below test procedure should be used:

- Center the frequency which was want to investigate, search the peak frequency.
- RBW: 1MHz (frequency range; 1GHz over), 100kHz (frequency range; 30MHz to 1GHz)
- VBW: Same as RBW (1MHz or 100kHz)
- Sweep time: Auto (Minimum time to ensure measurement accuracy. *In case of burst wave, one burst shall be included per data point)
- Sweep mode: Single Sweep
- Detection mode: Sample

Antenna Output Power and Antenna Power Tolerance

Limit

- $\leq 3 \text{ mW /MHz}$ (FHSS from 2402-2480 MHz)
- $\text{EIRP} \leq 6.91 \text{ dBm/MHz}$

The Output Power Tolerance must be within +20%, -80%.

Test Procedure

For FHSS UUT:

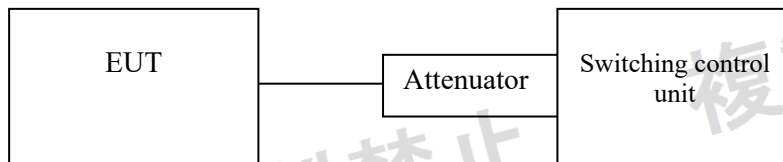
Step 1: Measure the total power by Power Meter in a state of hopping mode

Step 2: Set the power meter to trace average across the pulse on period, record the reading level on power meter.

Step 3: Calculate the mean power per 1MHz by dividing the reading level by spread bandwidth.

Output Power Density (mW/MHz) = Reading (mW) / Spread Bandwidth (MHz)

Test Setup Block diagram



Note: the power meter was integrated in the Switching control unit.

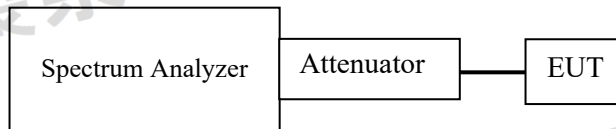
Receiver Spurious Emission and Unwanted Emission Intensity

Limit

- $\leq 4 \text{ nW}$ ($30 \text{ MHz} \leq f \leq 1000 \text{ MHz}$)
- $\leq 20 \text{ nW}$ ($1 \text{ GHz} \leq f \leq 12.5 \text{ GHz}$)

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be “continuous receiving mode”.

Spectrum Analyzer Conditions

- Start Frequency: Start Frequency of frequency range to measure (30MHz or 1GHz)
- Stop Frequency: Stop Frequency of frequency range to measure (1GHz or 12.5GHz)
- Span: AUTO (Measurement Range)
- RBW: 100 kHz, VBW: 100 kHz for Frequency < 1 GHz
- RBW: 1MHz, VBW: 1MHz for Frequency > 1 GHz
- Sweep time: AUTO or more
- Sweep mode: Auto Sweep
- Detection: Positive Peak
- Reference Level: Enough level for maximum dynamic range

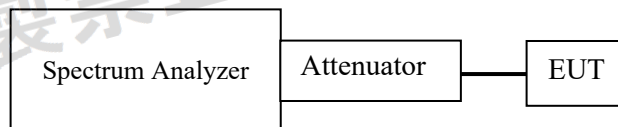
Frequency Hopping Dwell Time

Applicable Standard

According to Radio Law Radio Equipment Regulations Article 49-20, frequency dwell time is 0.4 seconds or below.

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- Set the application equipment (EUT) to the measurement frequency.
- The modulation state shall be “continuous (burst) transmission mode”. If impossible, it shall be “continuous frequency-hopping mode”.

Spectrum Analyzer Conditions

- Step 1:
 - Center Frequency: 2441.0 MHz
 - Span: ZERO SPAN
 - RBW: 1MHz, VBW: 3MHz
 - Log scale: 10dB/Div, Data points: 601points (400 points or more)
 - Reference level: Enough level for maximum dynamic range
 - Detection: Positive Peak,
 - Sweep mode: Single
- Step 2:
 - Center Frequency: 2441.0 MHz
 - RBW: 1MHz, VBW: 1MHz
 - Span: ZERO SPAN
 - Reference level: Enough level for maximum dynamic range
 - Detection: Positive Peak,
 - Sweep mode: Single
 - Sweep time: $0.4 * SBW[\text{second}]$

Dwell time = Time per one hopping (On time) * hopping numbers

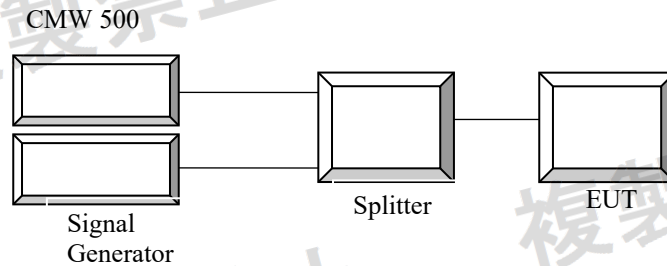
Interference Prevention Function

Requirement

The EUT shall have the interference prevention capability to transmit or to receive the identification automatically, so that sender and receiver shall exclude other equipment.

Test Procedure

Measurement System Diagram



In the case that the EUT has the function of automatically transmitting the identification code:

1. Transmit the predetermined identification codes from EUT
2. Check the transmitted identification codes with the demodulator.

In the case of receiving the identification codes:

1. Transmit the predetermined identification codes from the counterpart.
2. Check if communication is normal
3. Transmit the signal other than predetermined ID codes from the counterpart.
4. Check if the EUT stops the transmission, or if it displays that identification codes are different from the predetermined ones.

TEST DATA AND RESULTS

Frequency Error

Test Information:

Sample No.:	3EW4-3	Test Date:	2026/01/06
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.5	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.8
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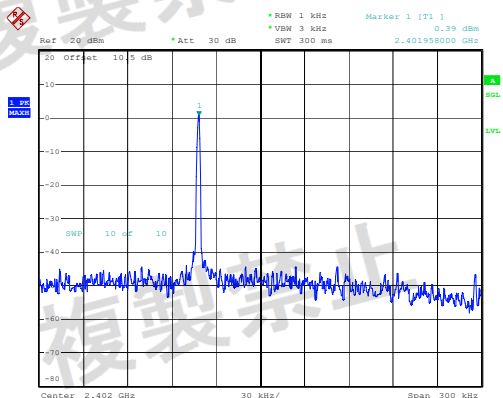
Test Condition: NV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.95800	-17.49	± 50	Pass
	2441	2440.95650	-17.82		Pass
	2480	2479.95538	-17.99		Pass

Frequency Tolerance = (Measure Frequency - Frequency)/Frequency*10⁶

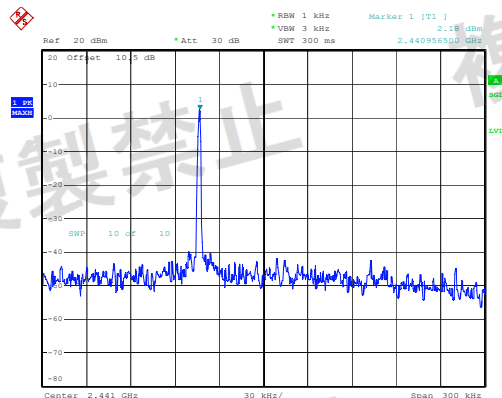
Test Condition: NV

2402MHz



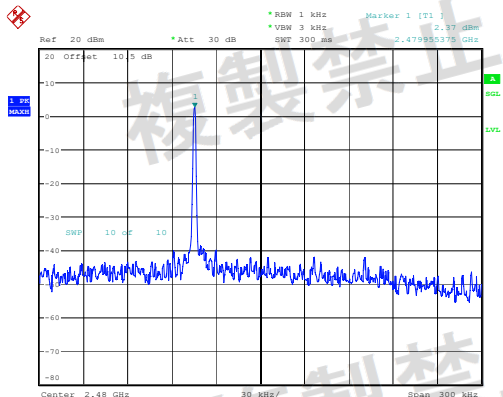
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:01:52

2441MHz



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:02:13

2480MHz



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:02:30

Occupied Bandwidth and Spreading Bandwidth**Test Information:**

Sample No.:	3EW4-3	Test Date:	2026/01/06
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.5	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.8
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Test Condition: NV

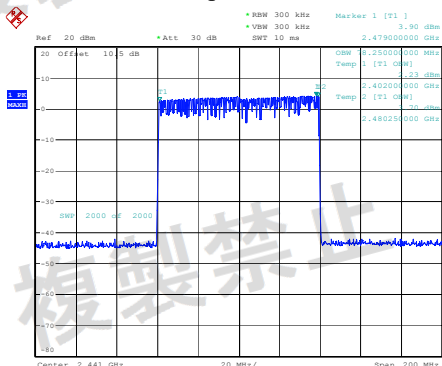
Mode	Packet Type	Occupied bandwidth (MHz)		Spreading bandwidth (MHz)		Spreading factor		Result
		Measured	Limit	Measured	Limit	Measured	Limit	
GFSK	DH1	78.25	≤ 83.5	71.00	≥ 0.5	71.00	> 5	Pass
	DH3	78.25	≤ 83.5	70.75	≥ 0.5	70.75	> 5	Pass
	DH5	78.25	≤ 83.5	71.00	≥ 0.5	71.00	> 5	Pass
$\pi/4$ - DQPSK	2DH1	78.5	≤ 83.5	71.25	≥ 0.5	71.25	> 5	Pass
	2DH3	78.5	≤ 83.5	71.25	≥ 0.5	71.25	> 5	Pass
	2DH5	78.5	≤ 83.5	71.50	≥ 0.5	71.50	> 5	Pass
8DPSK	3DH1	78.5	≤ 83.5	71.25	≥ 0.5	71.25	> 5	Pass
	3DH3	78.5	≤ 83.5	71.25	≥ 0.5	71.25	> 5	Pass
	3DH5	78.75	≤ 83.5	71.25	≥ 0.5	71.25	> 5	Pass

Note: Spread Factor = Spread Bandwidth/modulation rate. The modulation rate: MR=1.

Test Condition: NV

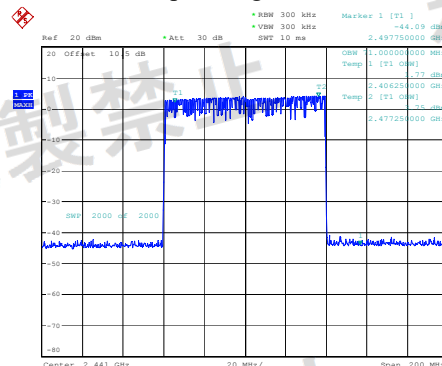
GFSK_Hopping_DH1

Occupied Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:34:20

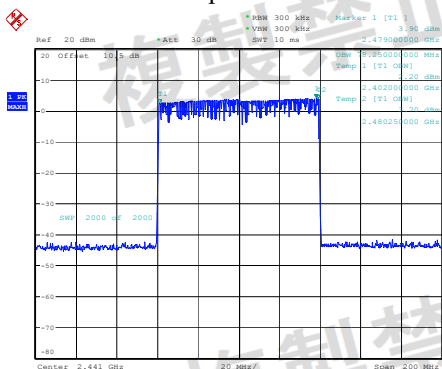
Spreading Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:36:49

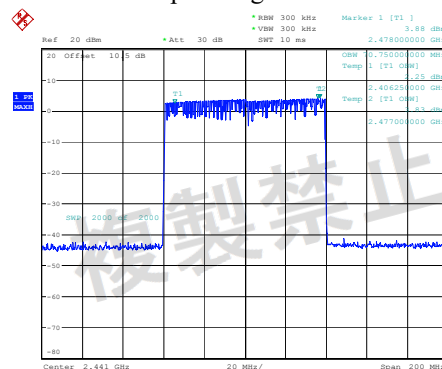
GFSK_Hopping_DH3

Occupied Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:38:05

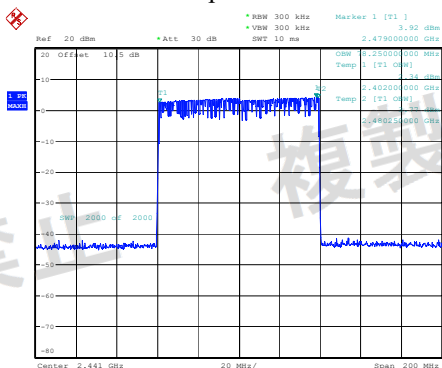
Spreading Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:39:03

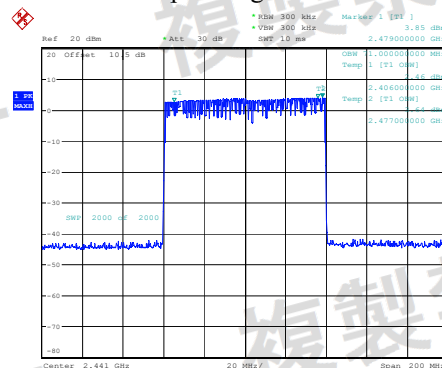
GFSK_Hopping_DH5

Occupied Bandwidth



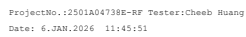
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:43:26

Spreading Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:44:24

Occupied Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:46:49

Occupied Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:50:32

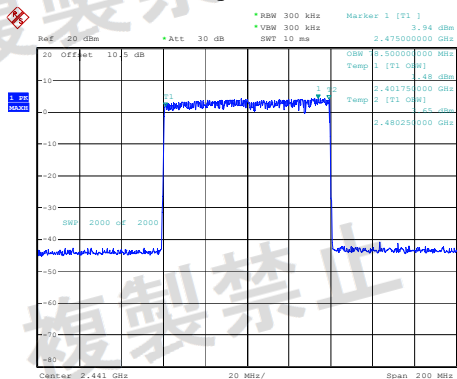
Occupied Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:53:00

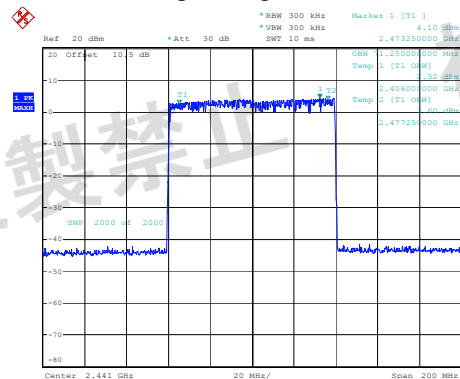
8DPSK_Hopping_3DH1

Occupied Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:55:58

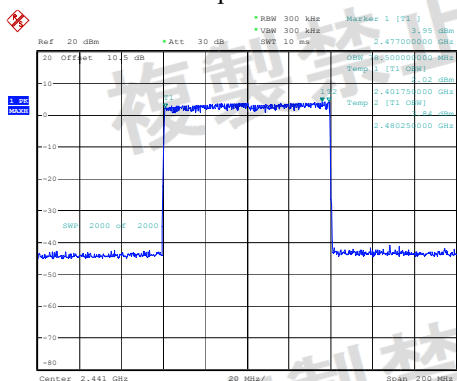
Spreading Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:56:57

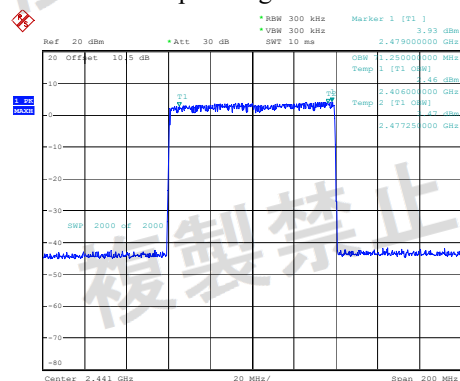
8DPSK_Hopping_3DH3

Occupied Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:58:25

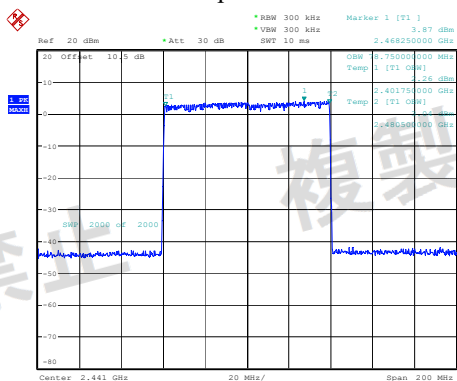
Spreading Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 11:59:58

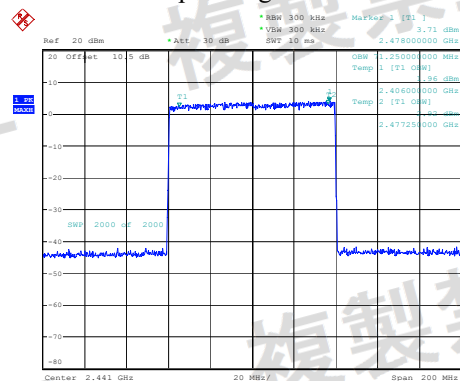
8DPSK_Hopping_3DH5

Occupied Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 12:03:29

Spreading Bandwidth



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 12:04:28

Transmitter Spurious Emission and Unwanted Emission Intensity**Test Information:**

Sample No.:	3EW4-3	Test Date:	2026/01/06
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.5	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.8
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Test Condition: NV, GFSK

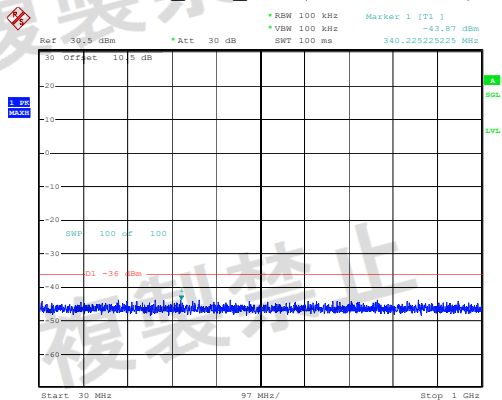
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located (MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	340.2252252	-43.87	0.041	0.25	Pass
	Band II (1MHz)	1000	2387	2373.1161000	-38.17	0.152	2.50	Pass
	Band III (1MHz)	2387	2400	2400.0	-20.34	9.247	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2487.7422000	-37.77	0.167	25	Pass
	Band V (1MHz)	2496.5	12500	4804.6149000	-33.62	0.435	2.50	Pass
Middle	Band I (100kHz)	30	1000	653.8488488	-43.74	0.042	0.25	Pass
	Band II (1MHz)	1000	2387	2277.3173000	-39.10	0.123	2.50	Pass
	Band III (1MHz)	2387	2400	2387.1366000	-38.14	0.153	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2485.6406000	-37.24	0.189	25	Pass
	Band V (1MHz)	2496.5	12500	4879.7162000	-33.03	0.498	2.50	Pass
High	Band I (100kHz)	30	1000	401.8818819	-43.83	0.041	0.25	Pass
	Band II (1MHz)	1000	2387	2249.5495000	-39.40	0.115	2.50	Pass
	Band III (1MHz)	2387	2400	2396.0375000	-37.89	0.163	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.0400000	-36.15	0.243	25	Pass
	Band V (1MHz)	2496.5	12500	4959.8243000	-33.56	0.441	2.50	Pass

Test Condition: NV, $\pi/4$ -DQPSK

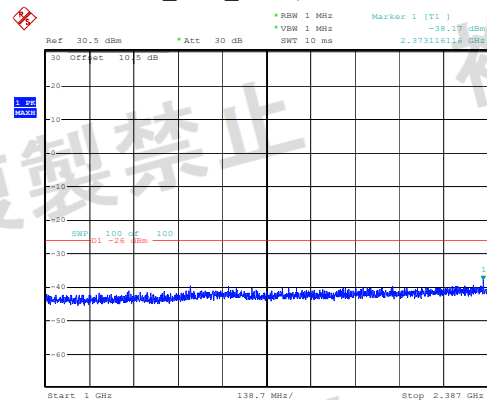
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located (MHz)	Result (dBm/RBW)	Result (μ W/RBW)	Limit (μ W/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	320.8058058	-43.49	0.045	0.25	Pass
	Band II (1MHz)	1000	2387	2376.5871000	-39.18	0.121	2.50	Pass
	Band III (1MHz)	2387	2400	2400.0	-22.73	5.333	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.8604000	-37.34	0.185	25	Pass
	Band V (1MHz)	2496.5	12500	4804.6149000	-32.58	0.552	2.50	Pass
Middle	Band I (100kHz)	30	1000	590.7357357	-43.68	0.043	0.25	Pass
	Band II (1MHz)	1000	2387	2222.4760000	-39.20	0.120	2.50	Pass
	Band III (1MHz)	2387	2400	2392.0360000	-38.19	0.152	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2495.2768000	-37.35	0.184	25	Pass
	Band V (1MHz)	2496.5	12500	4879.7162000	-30.83	0.826	2.50	Pass
High	Band I (100kHz)	30	1000	759.6846847	-43.20	0.048	0.25	Pass
	Band II (1MHz)	1000	2387	2348.8193000	-38.23	0.150	2.50	Pass
	Band III (1MHz)	2387	2400	2387.9369000	-38.34	0.147	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.7753000	-33.88	0.409	25	Pass
	Band V (1MHz)	2496.5	12500	11743.9797000	-37.25	0.188	2.50	Pass

Test Condition: NV, 8DPSK

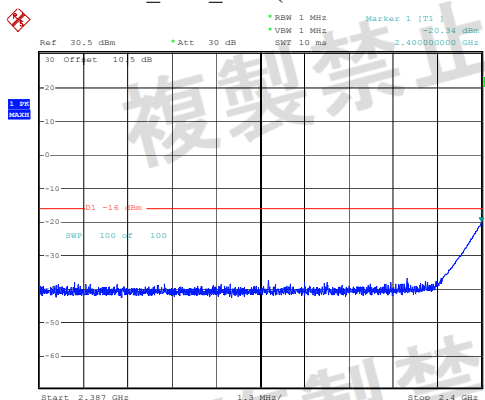
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located (MHz)	Result (dBm/RBW)	Result (μ W/RBW)	Limit (μ W/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	753.3733734	-43.70	0.043	0.25	Pass
	Band II (1MHz)	1000	2387	2346.7367000	-38.25	0.150	2.50	Pass
	Band III (1MHz)	2387	2400	2400.0	-21.28	7.446	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2492.1341000	-37.84	0.164	25	Pass
	Band V (1MHz)	2496.5	12500	4804.6149000	-31.40	0.724	2.50	Pass
Middle	Band I (100kHz)	30	1000	827.6526527	-43.53	0.044	0.25	Pass
	Band II (1MHz)	1000	2387	2287.7302000	-39.09	0.123	2.50	Pass
	Band III (1MHz)	2387	2400	2388.4640000	-38.23	0.150	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.4374000	-37.37	0.183	25	Pass
	Band V (1MHz)	2496.5	12500	4879.7162000	-31.38	0.728	2.50	Pass
High	Band I (100kHz)	30	1000	662.1021021	-43.36	0.046	0.25	Pass
	Band II (1MHz)	1000	2387	2221.0876000	-39.07	0.124	2.50	Pass
	Band III (1MHz)	2387	2400	2389.6547000	-38.29	0.148	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2490.4880000	-38.03	0.157	25	Pass
	Band V (1MHz)	2496.5	12500	12064.4122000	-36.68	0.215	2.50	Pass

Test Condition: NV**GFSK_Low_DH1(30MHz~1GHz)**

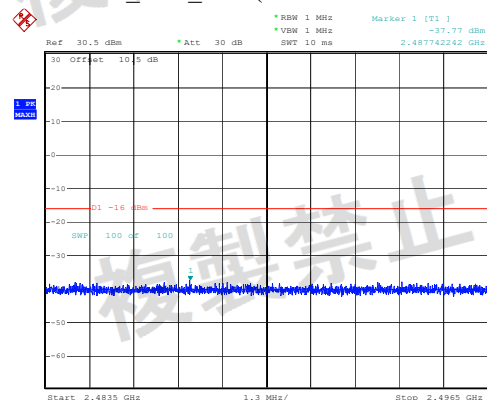
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:05:43

GFSK_Low_DH1(1GHz~2.387GHz)

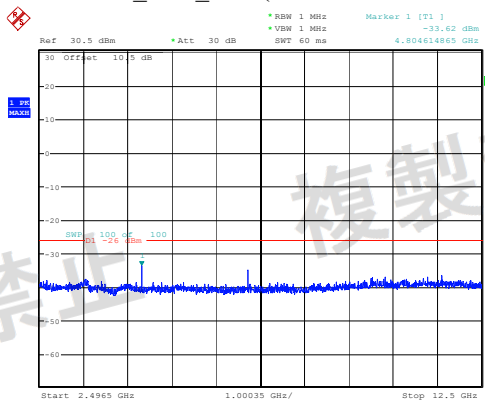
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:05:53

GFSK_Low_DH1(2.387GHz~2.4GHz)

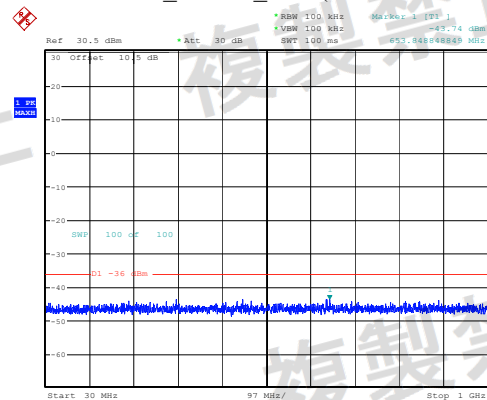
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:06:01

GFSK_Low_DH1(2.4835GHz~2.4965GHz)

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:06:09

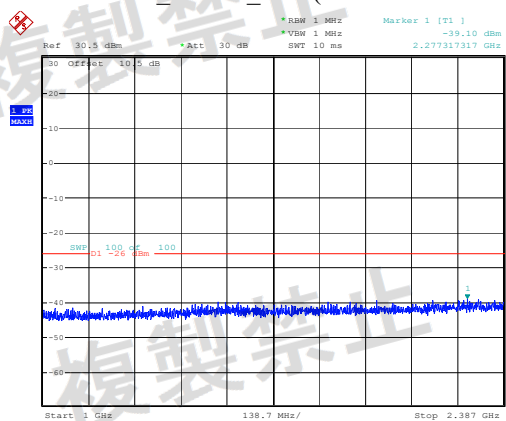
GFSK_Low_DH1(2.4965GHz~12.5GHz)

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:06:34

GFSK_Middle_DH1(30MHz~1GHz)

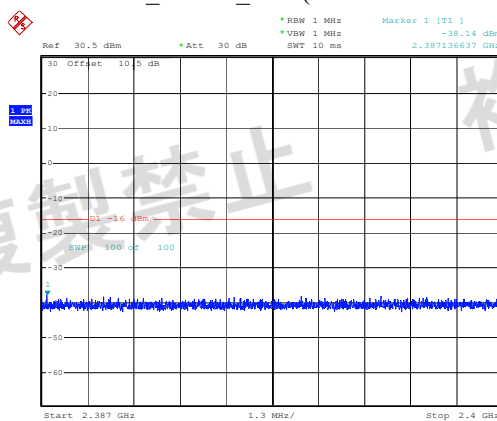
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:07:09

GFSK_Middle_DH1(1GHz~2.387GHz)



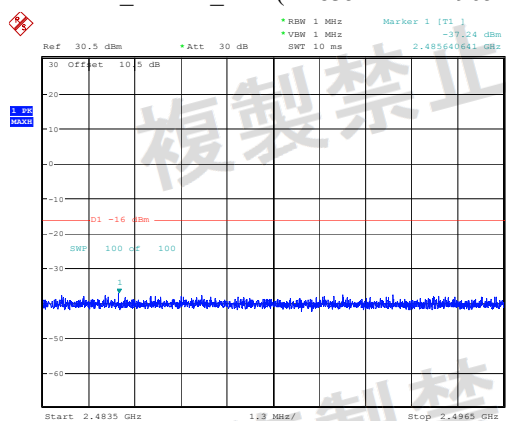
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:07:20

GFSK_Middle_DH1(2.387GHz~2.4GHz)



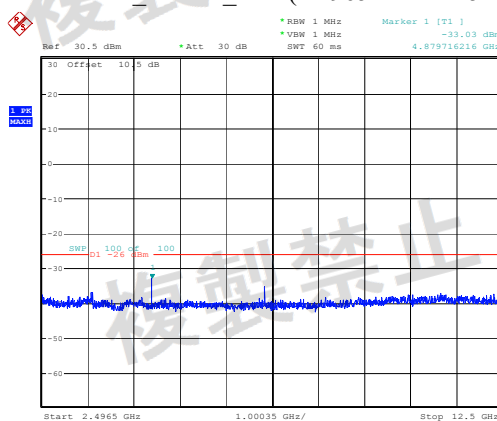
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:07:29

GFSK_Middle_DH1(2.4835GHz~2.4965GHz)



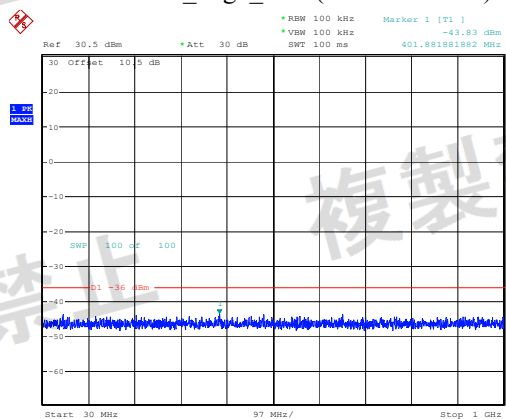
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:07:37

GFSK_Middle_DH1(2.4965GHz~12.5GHz)



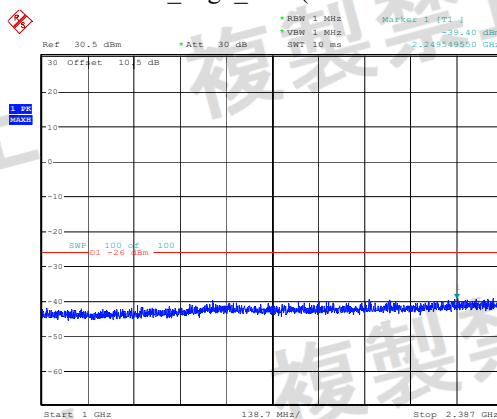
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:08:03

GFSK_High_DH1(30MHz~1GHz)



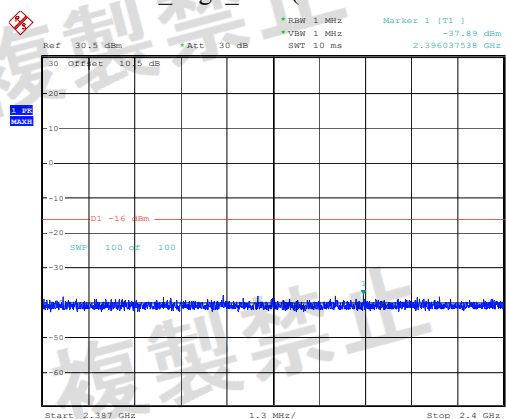
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:09:03

GFSK_High_DH1(1GHz~2.387GHz)



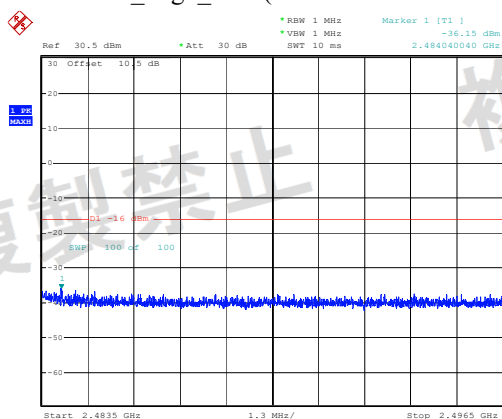
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:09:13

GFSK_High_DH1(2.387GHz~2.4GHz)



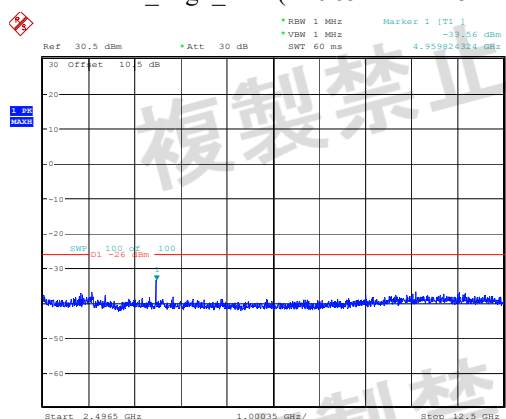
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:09:22

GFSK_High_DH1(2.4835GHz~2.4965GHz)

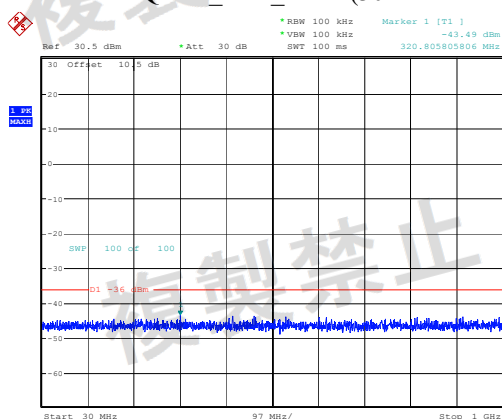


ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:09:31

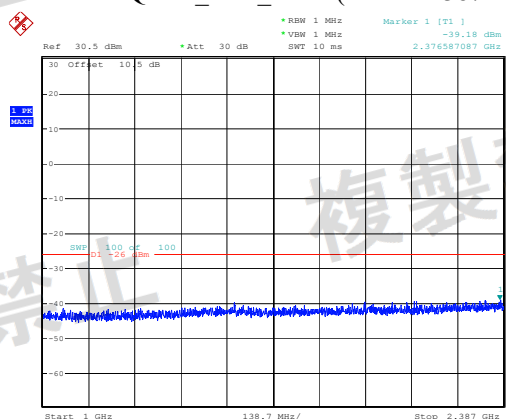
GFSK_High_DH1(2.4965GHz~12.5GHz)



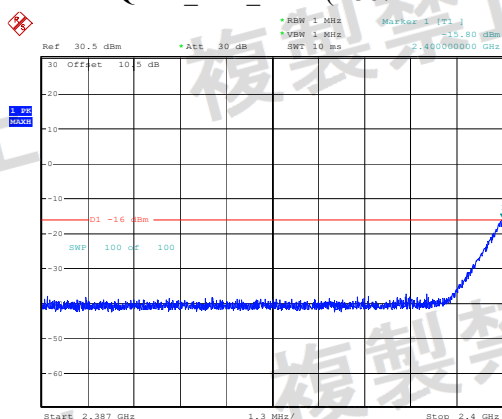
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:09:56

 $\pi/4$ -DQPSK_Low_2DH1(30MHz~1GHz)

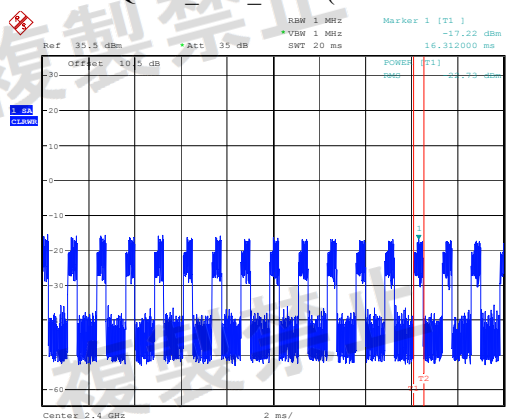
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:21:55

 $\pi/4$ -DQPSK_Low_2DH1(1GHz~2.387GHz)

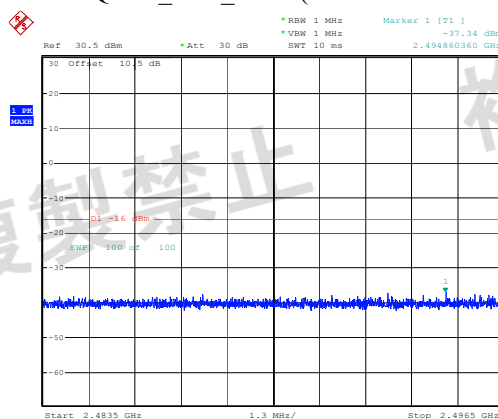
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:22:06

 $\pi/4$ -DQPSK_Low_2DH1(2.387GHz~2.4GHz)

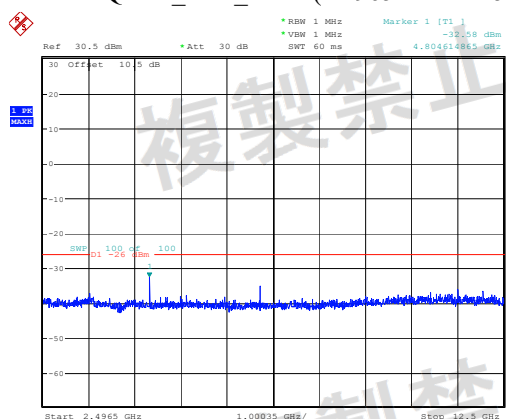
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:29:40

$\pi/4$ -DQPSK_Low_2DH1(2.387GHz~2.4GHz)

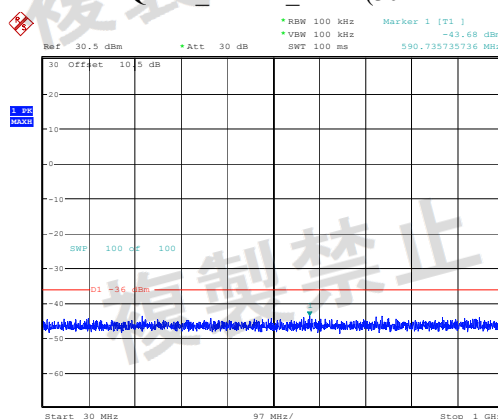
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:33:21

 $\pi/4$ -DQPSK_Low_2DH1(2.4835GHz~2.4965GHz)

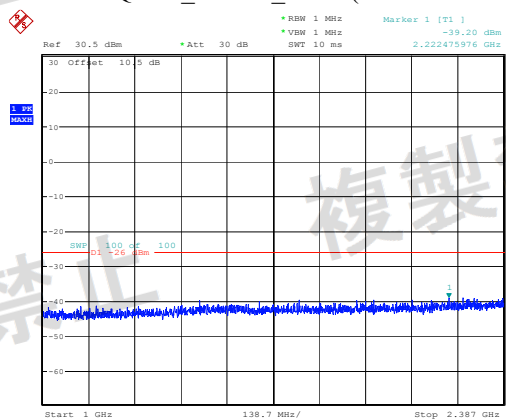
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:33:29

 $\pi/4$ -DQPSK_Low_2DH1(2.4965GHz~12.5GHz)

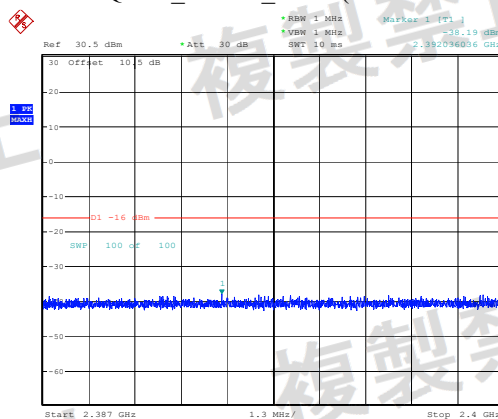
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:33:55

 $\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)

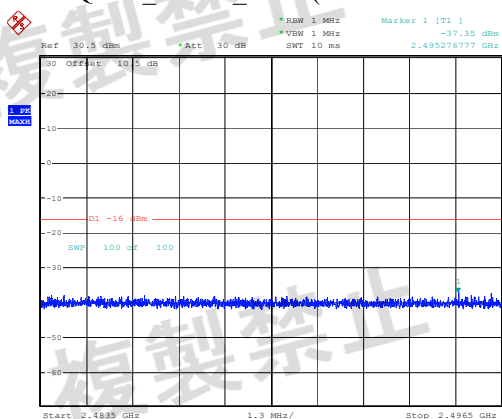
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:35:00

 $\pi/4$ -DQPSK_Middle_2DH1(1GHz~2.387GHz)

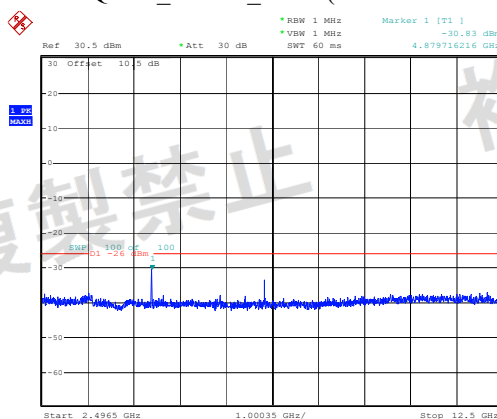
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:35:11

 $\pi/4$ -DQPSK_Middle_2DH1(2.387GHz~2.4GHz)

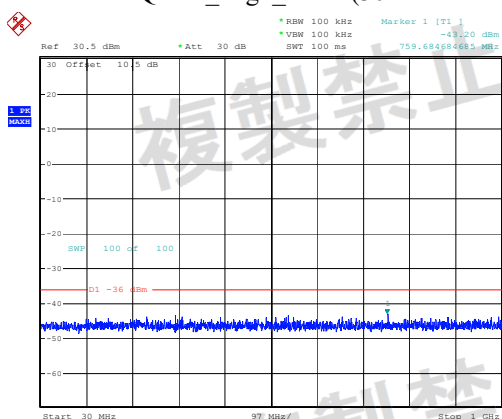
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:35:20

$\pi/4$ -DQPSK_Middle_2DH1(2.4835GHz~2.4965GHz)

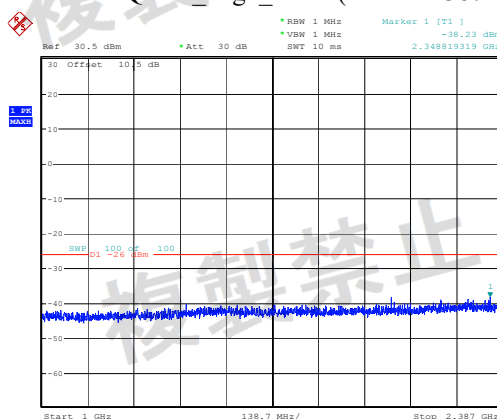
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:35:28

 $\pi/4$ -DQPSK_Middle_2DH1(2.4965GHz~12.5GHz)

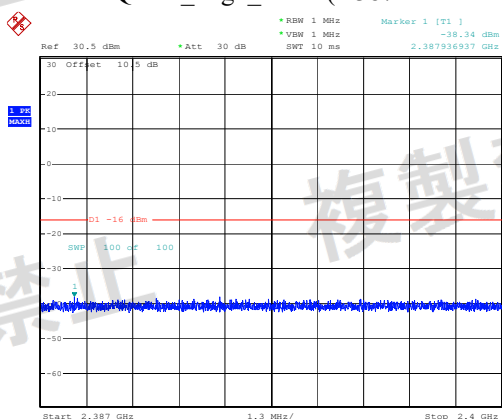
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:35:53

 $\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)

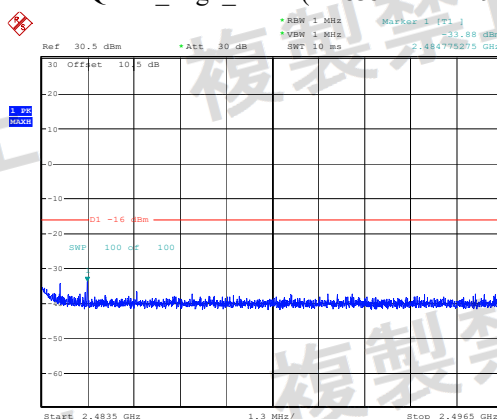
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:36:20

 $\pi/4$ -DQPSK_High_2DH1(1GHz~2.387GHz)

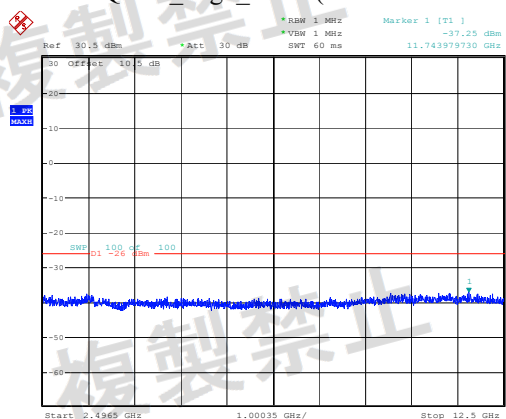
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:36:31

 $\pi/4$ -DQPSK_High_2DH1(2.387GHz~2.4GHz)

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:36:40

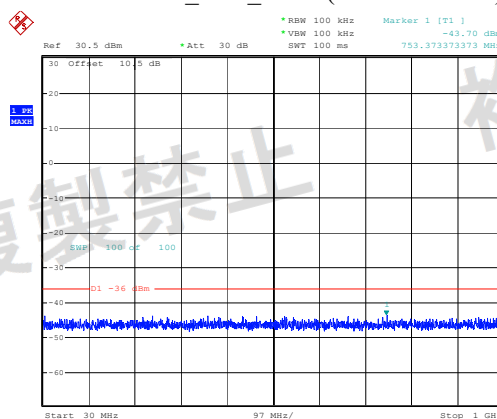
 $\pi/4$ -DQPSK_High_2DH1(2.4835GHz~2.4965GHz)

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:37:55

$\pi/4$ -DQPSK_High_2DH1(2.4965GHz~12.5GHz)

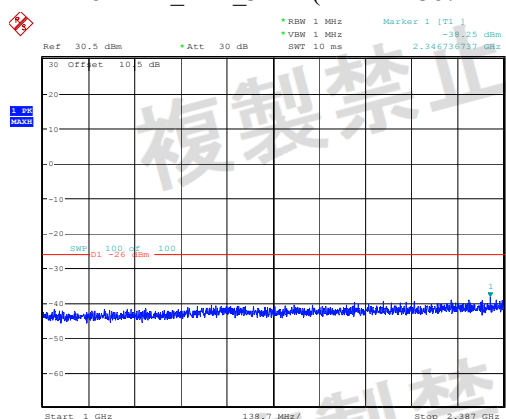
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:37:13

8DPSK_Low_3DH1(30MHz~1GHz)



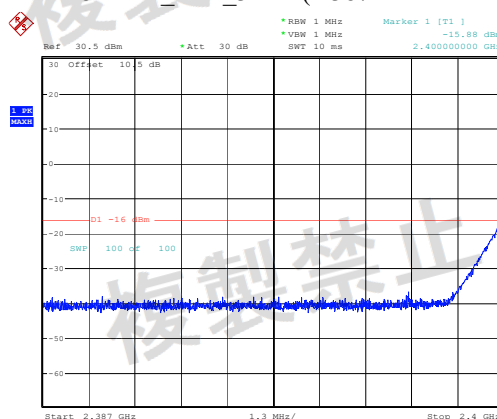
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:38:33

8DPSK_Low_3DH1(1GHz~2.387GHz)



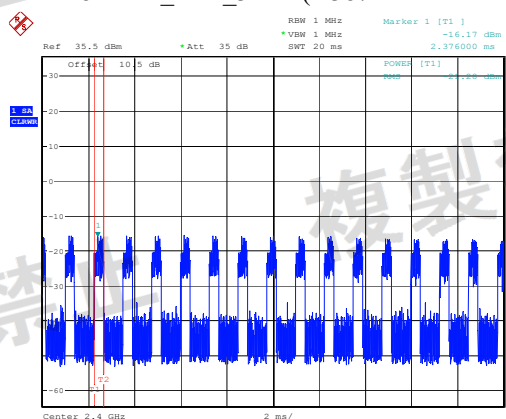
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:38:44

8DPSK_Low_3DH1(2.387GHz~2.4GHz)



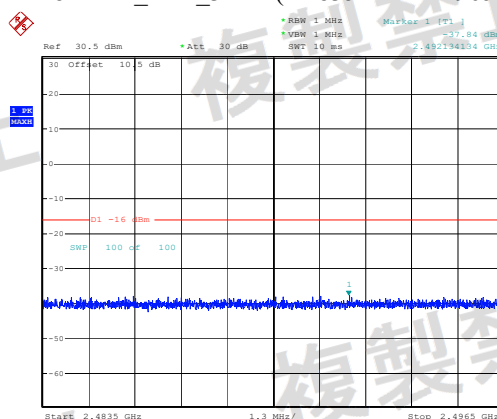
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:38:52

8DPSK_Low_3DH1(2.387GHz~2.4GHz)



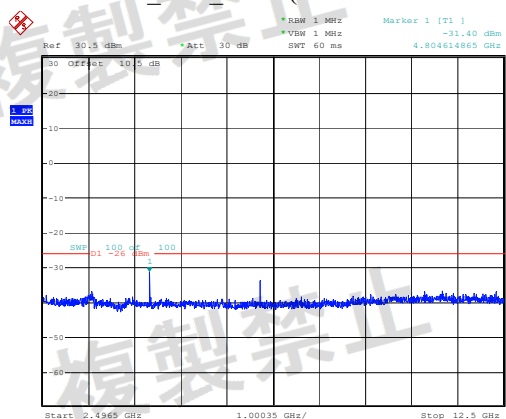
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:40:11

8DPSK_Low_3DH1(2.4835GHz~2.4965GHz)



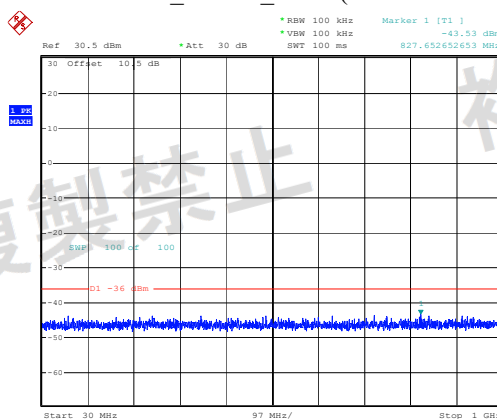
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:40:20

8DPSK_Low_3DH1(2.4965GHz~12.5GHz)



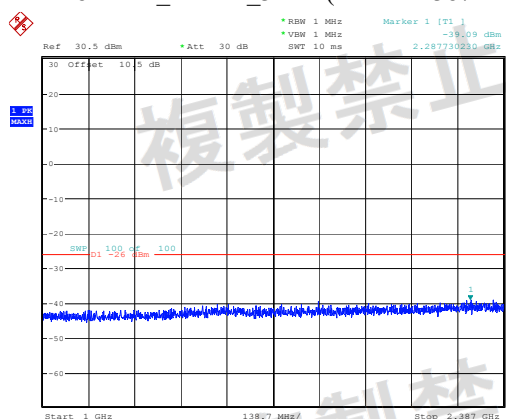
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:40:45

8DPSK_Middle_3DH1(30MHz~1GHz)



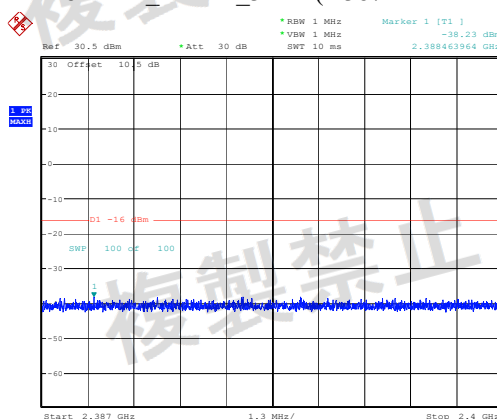
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:41:15

8DPSK_Middle_3DH1(1GHz~2.387GHz)



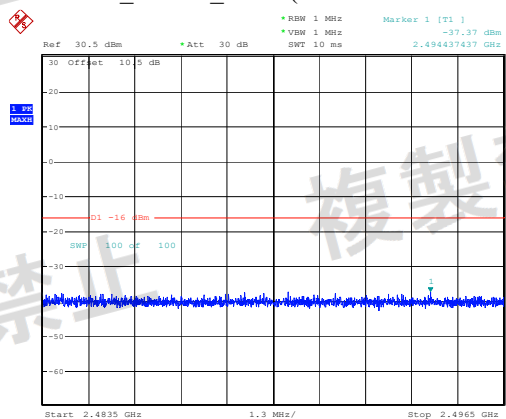
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:41:25

8DPSK_Middle_3DH1(2.387GHz~2.4GHz)



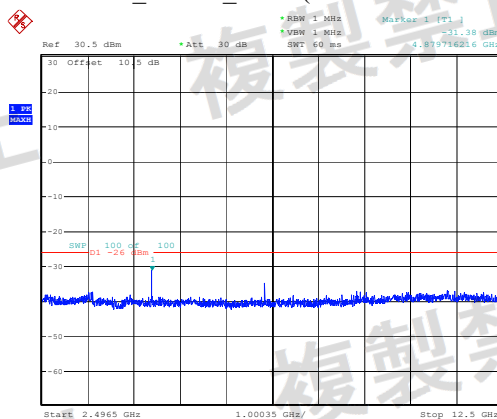
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:41:34

8DPSK_Middle_3DH1(2.4835GHz~2.4965GHz)

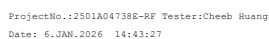
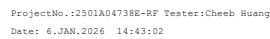
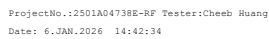


ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:41:42

8DPSK_Middle_3DH1(2.4965GHz~12.5GHz)



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:42:08



Antenna Output Power and Output Power Tolerance**Test Information:**

Sample No.:	3EW4-3	Test Date:	2026/01/06
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.5	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.8
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Test Condition: NV

Mode	Antenna gain (dBi)	Declared power (mW/MHz)
GFSK	3.37	0.030
$\pi/4$ DQPSK		0.030
8DPSK		0.030

Mode	Antenna output power (dBm)	Spread bandwidth (MHz)	Antenna output power (mW/MHz)		Antenna output power tolerance(%)		EIRP (dBm/MHz)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
GFSK	3.39	71.000	0.031	≤ 3	3.33	-80~+20	-11.72	≤ 6.91	Pass
$\pi/4$ - DQPSK	3.05	71.250	0.028	≤ 3	-6.67	-80~+20	-12.16	≤ 6.91	Pass
8DPSK	3.25	71.250	0.030	≤ 3	0.0	-80~+20	-11.86	≤ 6.91	Pass

Note:

Antenna output power(mW) = $10^{\{\text{Antenna output power(dBm)} / 10\}}$

Antenna output power(mW/MHz) = Antenna output power(mW) / Spread bandwidth(MHz)

Antenna output power Tolerance(%) = (Antenna output power(mW/MHz) - Declared power) / Declared power * 100%

Antenna output power(dBm/MHz) = $10 * \log_{10}\{\text{Antenna output power(mW/MHz)}\}$

EIRP(dBm/MHz) = Antenna output power(dBm/MHz) + Antenna gain.

Receiver Spurious Emission and Unwanted Emission Intensity**Test Information:**

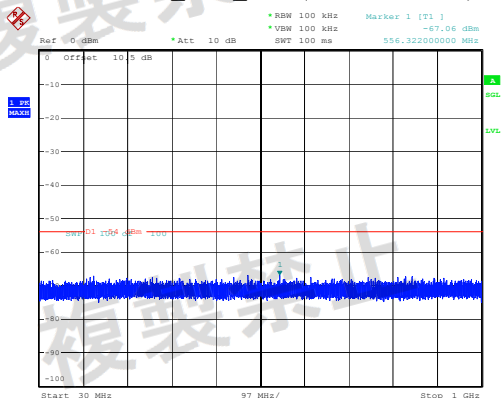
Sample No.:	3EW4-3	Test Date:	2026/01/06
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

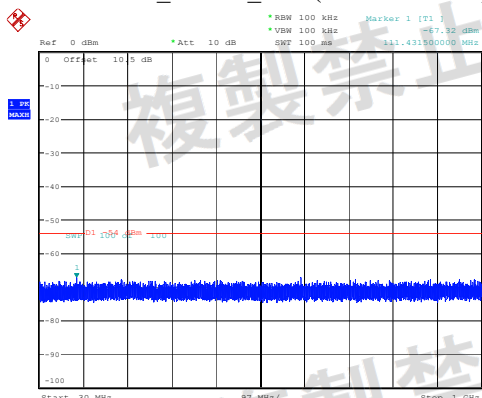
Temperature: (°C)	25.5	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.8
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Test Condition: NV

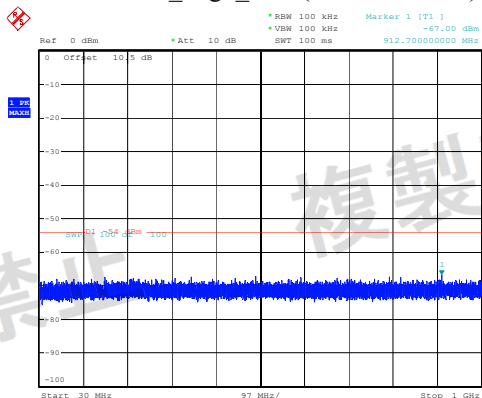
Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located (MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start (MHz)	Stop (MHz)					
GFSK	Low	Band I (100kHz)	30	1000	556.322	-67.06	0.197	4	Pass
		Band II (1MHz)	1000	12500	3410.4	-56.94	2.023	20	Pass
	Middle	Band I (100kHz)	30	1000	111.4315	-67.32	0.185	4	Pass
		Band II (1MHz)	1000	12500	3567.95	-58.52	1.406	20	Pass
	High	Band I (100kHz)	30	1000	912.7	-67.00	0.200	4	Pass
		Band II (1MHz)	1000	12500	11244.775	-57.54	1.762	20	Pass
$\pi/4$ - DQPSK	Low	Band I (100kHz)	30	1000	824.7695	-65.12	0.308	4	Pass
		Band II (1MHz)	1000	12500	11324.125	-57.79	1.663	20	Pass
	Middle	Band I (100kHz)	30	1000	666.805	-66.98	0.200	4	Pass
		Band II (1MHz)	1000	12500	11317.8	-56.31	2.339	20	Pass
	High	Band I (100kHz)	30	1000	991.7065	-65.57	0.277	4	Pass
		Band II (1MHz)	1000	12500	3589.225	-57.57	1.750	20	Pass
8DPSK	Low	Band I (100kHz)	30	1000	804.545	-66.49	0.224	4	Pass
		Band II (1MHz)	1000	12500	12077.375	-57.69	1.702	20	Pass
	Middle	Band I (100kHz)	30	1000	438.8065	-66.51	0.223	4	Pass
		Band II (1MHz)	1000	12500	9529.55	-57.94	1.607	20	Pass
	High	Band I (100kHz)	30	1000	223.7575	-66.92	0.203	4	Pass
		Band II (1MHz)	1000	12500	11255.125	-57.60	1.738	20	Pass

Test Condition: NV**GFSK_Low_DH1(30MHz~1GHz)**

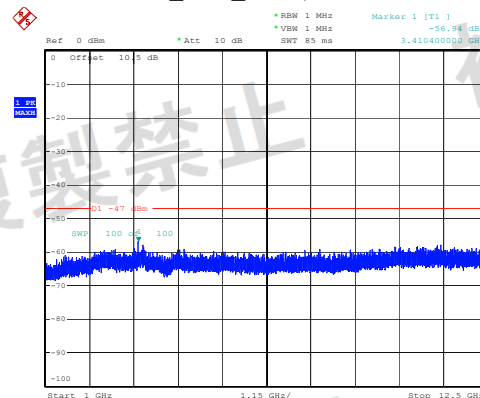
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:45:34

GFSK_Middle_DH1(30MHz~1GHz)

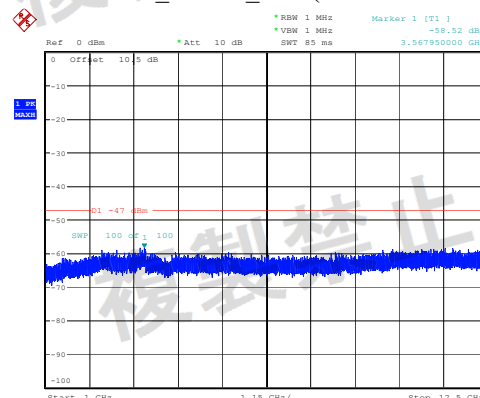
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:46:31

GFSK_High_DH1(30MHz~1GHz)

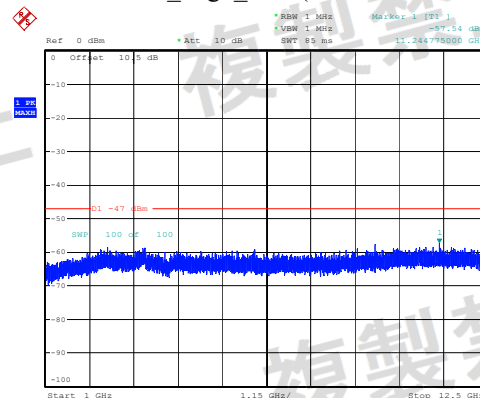
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:47:28

GFSK_Low_DH1(1GHz~12.5GHz)

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:46:06

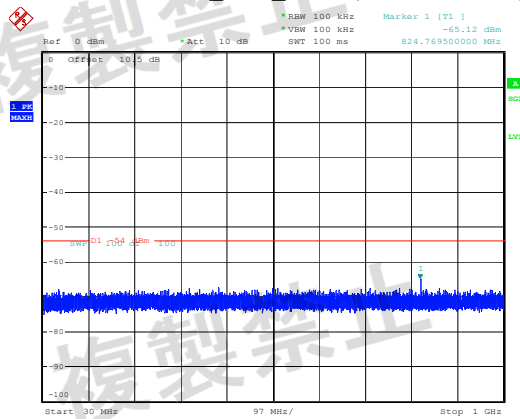
GFSK_Middle_DH1(1GHz~12.5GHz)

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:47:03

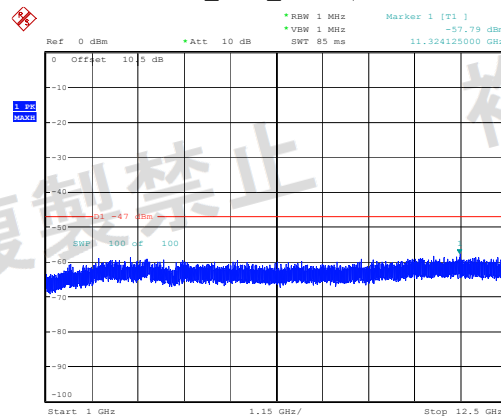
GFSK_High_DH1(1GHz~12.5GHz)

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:48:00

$\pi/4$ -DQPSK_Low_2DH1(30MHz~1GHz)

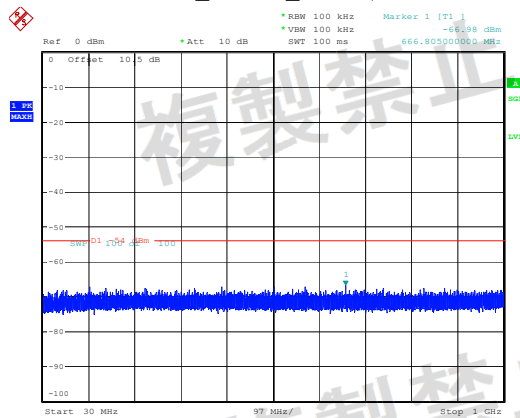


ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:48:58

 $\pi/4$ -DQPSK_Low_2DH1(1GHz~12.5GHz)

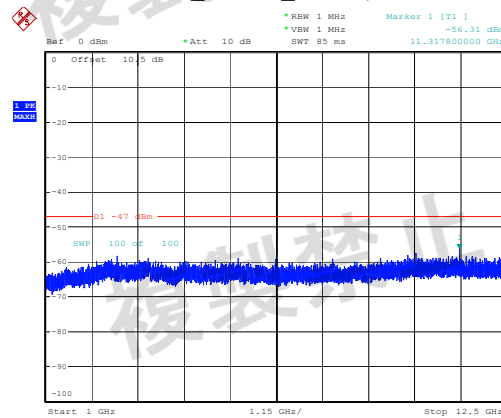
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:49:30

$\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)



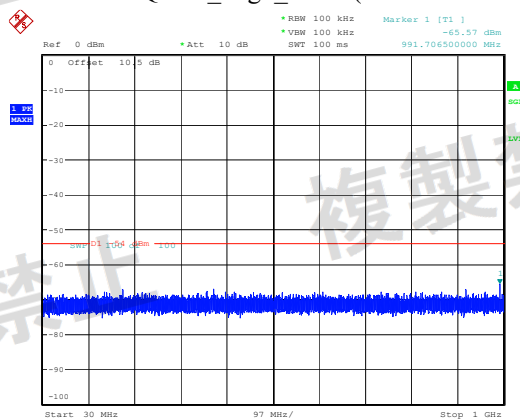
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:49:53

$\pi/4$ -DQPSK_Middle_2DH1(1GHz~12.5GHz)



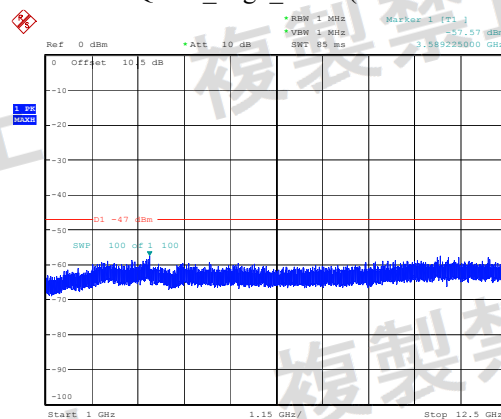
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:50:24

$\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)



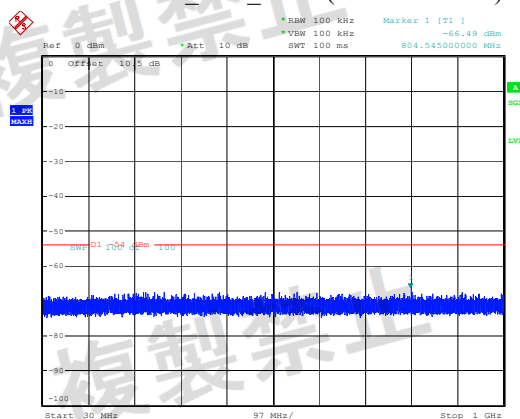
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:50:52

$\pi/4$ -DQPSK_High_2DH1(1GHz~12.5GHz)



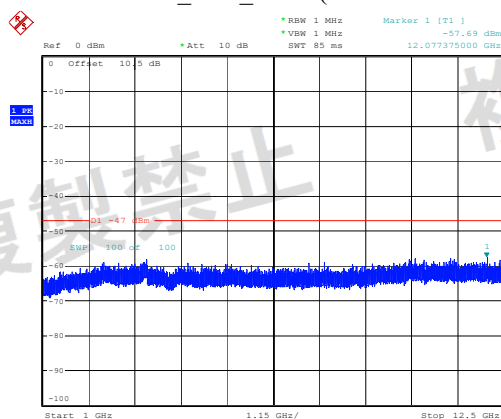
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:51:24

8DPSK_Low_3DH1(30MHz~1GHz)



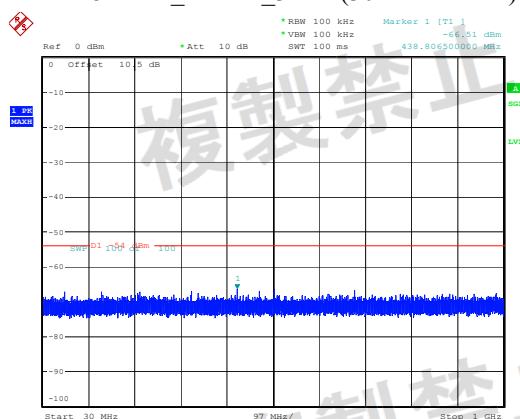
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:51:47

8DPSK_Low_3DH1(1GHz~12.5GHz)



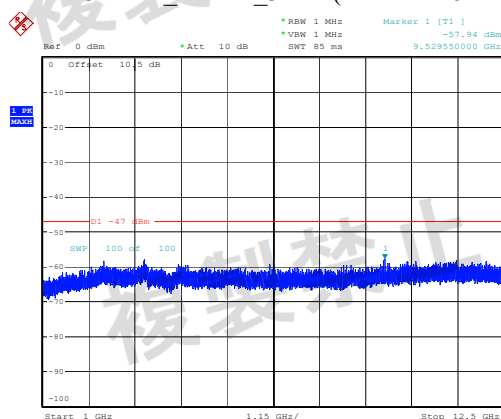
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:52:19

8DPSK_Middle_3DH1(30MHz~1GHz)



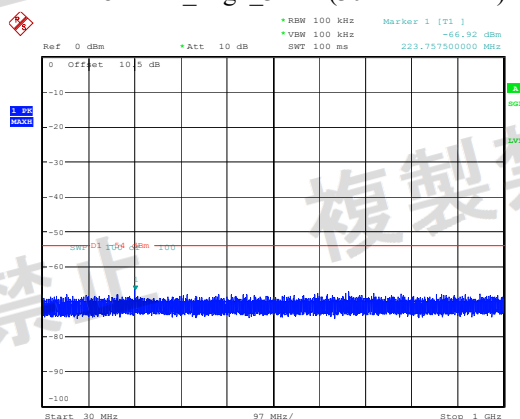
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:52:44

8DPSK_Middle_3DH1(1GHz~12.5GHz)



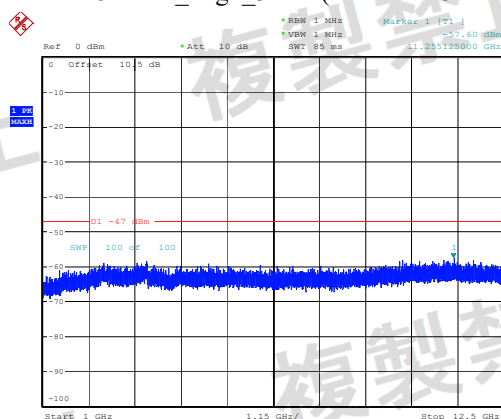
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:53:16

8DPSK_High_3DH1(30MHz~1GHz)



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:53:44

8DPSK_High_3DH1(1GHz~12.5GHz)



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 14:54:16

Frequency Hopping Dwell Time**Test Information:**

Sample No.:	3EW4-3	Test Date:	2026/01/06
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.5	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.8
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Test Condition: NV

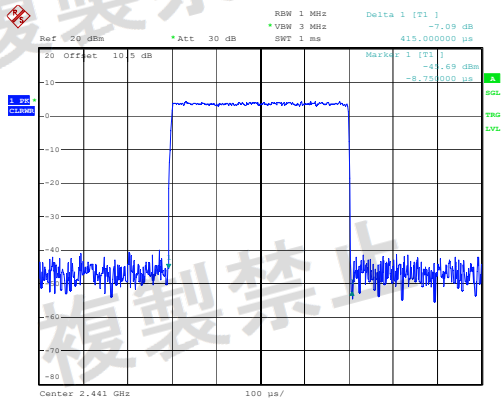
Mode	Packet Type	Spreading bandwidth	Ton (ms)	Observed Period(s)	Hopping Number In Observed Period	Result (s)	Limit(s)	Verdict
GFSK	DH1	71.0000	0.415	28.4000	178	0.074	≤ 0.4	Pass
	DH3	70.7500	1.684	28.3000	109	0.184		Pass
	DH5	71.0000	2.944	28.4000	75	0.221		Pass
$\pi/4$ -DQPSK	2DH1	71.2500	0.425	28.5000	176	0.075		Pass
	2DH3	71.2500	1.688	28.5000	116	0.196		Pass
	2DH5	71.5000	2.956	28.6000	93	0.275		Pass
8DPSK	3DH1	71.2500	0.426	28.5000	187	0.080		Pass
	3DH3	71.2500	1.684	28.5000	115	0.194		Pass
	3DH5	71.2500	2.956	28.5000	82	0.242		Pass

Note:

1. Dwell time = Time per one hopping (Ton) * hopping number (within the time obtained by multiplying the spread bandwidth by 0.4s).
2. The Spread Bandwidth please refer to Occupied Bandwidth and Spreading Bandwidth.

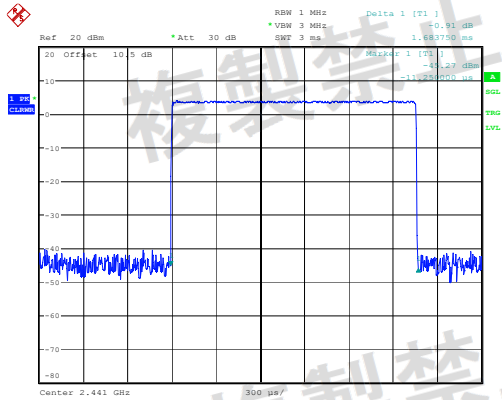
Test Condition: NV

GFSK_Hopping_DH1



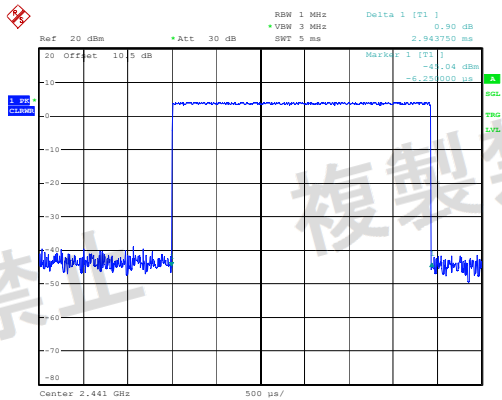
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:09:35

GFSK_Hopping_DH3



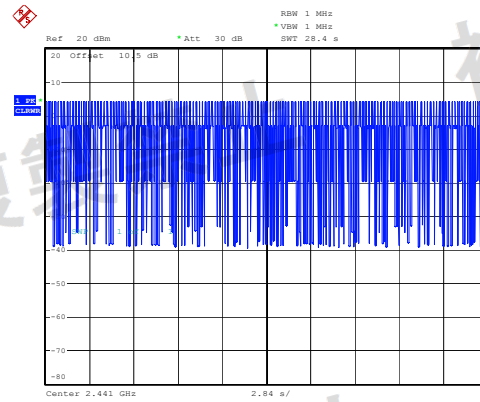
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:13:08

GFSK_Hopping_DH5



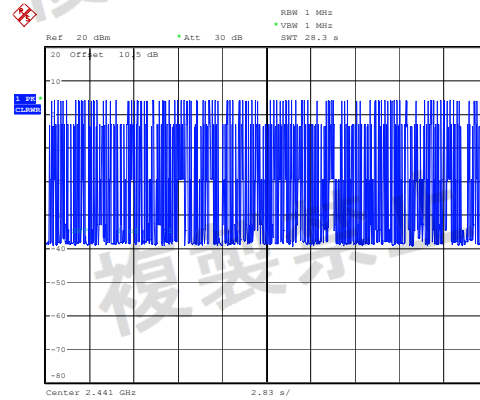
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:14:28

GFSK_Hopping_DH1



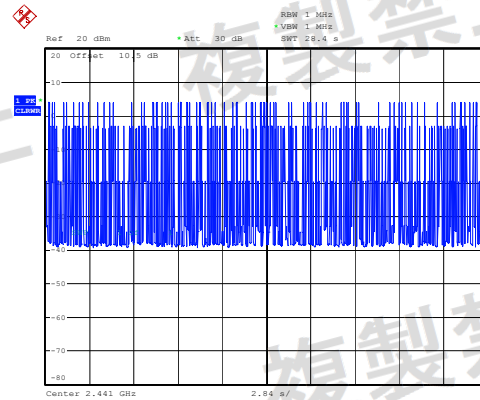
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:10:09

GFSK_Hopping_DH3

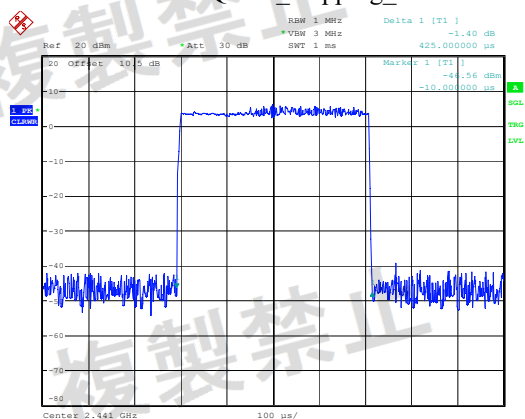


ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:13:40

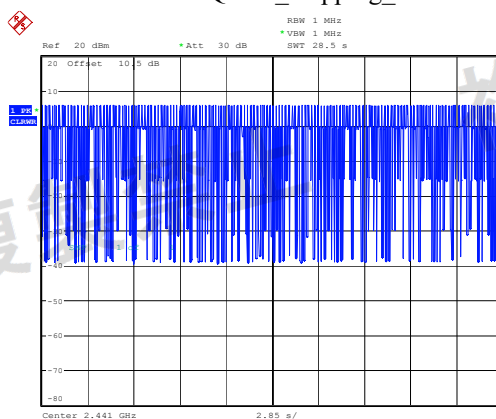
GFSK_Hopping_DH5



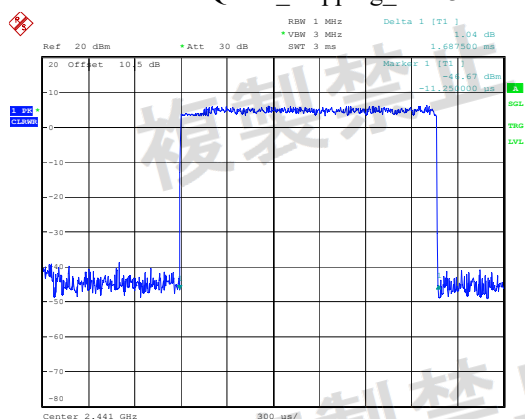
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:15:01

$\pi/4$ -DQPSK_Hopping_2DH1

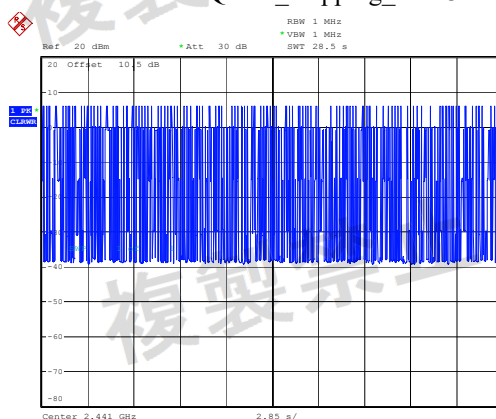
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:15:59

 $\pi/4$ -DQPSK_Hopping_2DH1

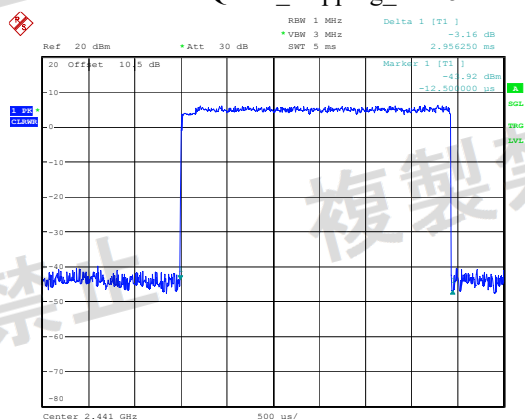
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:16:32

 $\pi/4$ -DQPSK_Hopping_2DH3

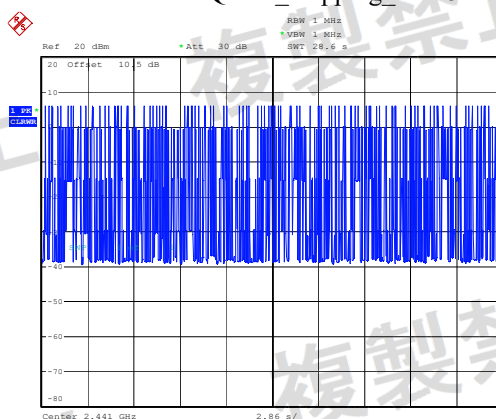
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:21:39

 $\pi/4$ -DQPSK_Hopping_2DH3

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:22:11

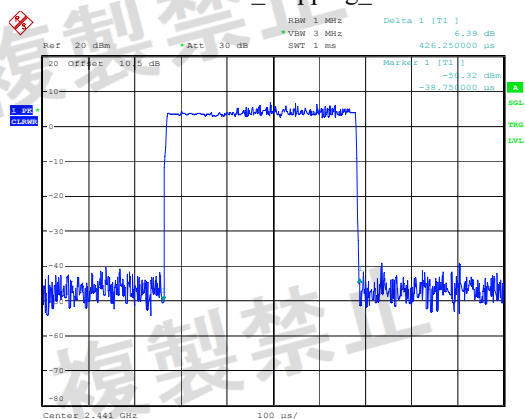
 $\pi/4$ -DQPSK_Hopping_2DH5

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:25:07

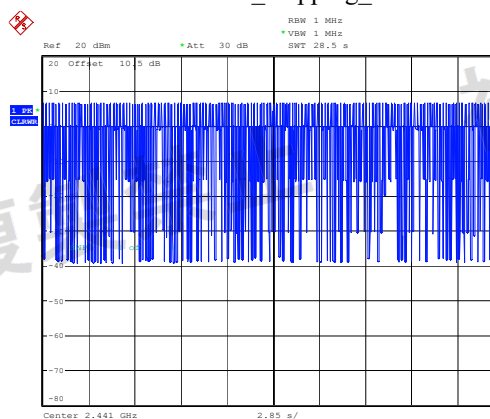
 $\pi/4$ -DQPSK_Hopping_2DH5

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:25:40

8DPSK_Hopping_3DH1



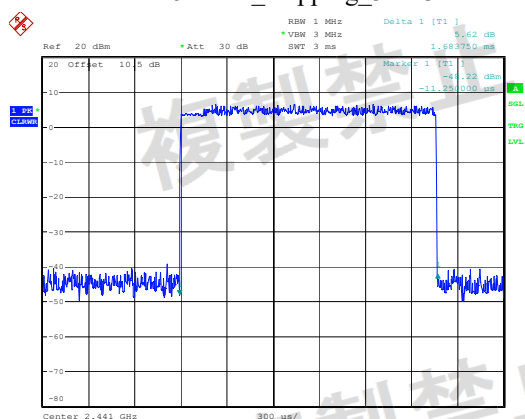
8DPSK_Hopping_3DH1



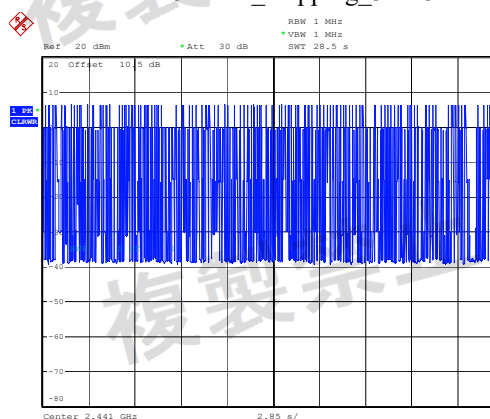
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:26:25

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:26:57

8DPSK_Hopping_3DH3



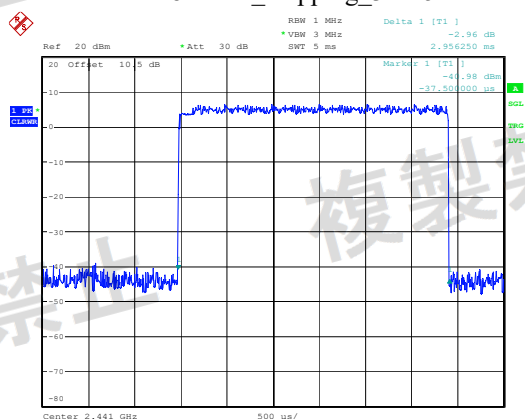
8DPSK_Hopping_3DH3



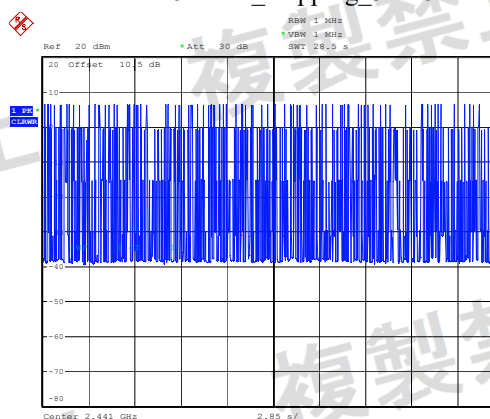
ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:27:42

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:28:15

8DPSK_Hopping_3DH5



8DPSK_Hopping_3DH5



ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:30:52

ProjectNo.:2501A04738E-RF Tester:Cheeb Huang
Date: 6.JAN.2026 13:31:24

Interference Prevention Function**Test Information:**

Sample No.:	3EW4-3	Test Date:	2026/01/06
Test Site:	RF	Test Mode:	Communicating
Tester:	Cheeb Huang	Test Result:	Good

Environmental Conditions:

Temperature: (°C)	25.5	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.8
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Test Result: Good

CONSTRUCTION PROTECTION CONFIRMATION

Limit

The high-frequency section and modulation section of the radio equipment except for the antenna system shall not be capable of being opened easily.

Confirmation Result

The EUT cover was fixed by the screws which can't be opened easily, please see the EUT photos.

EUT PHOTOGRAPHS

Please refer to the attachment 2501A04738E-RF-EXP External photo and 2501A04738E-RF-INP Internal photo.

TEST SETUP PHOTOGRAPHS

Please refer to the attachment 2501A04738E-RF-07-TSP Test Setup photo.

****END OF REPORT****